PCN Number:	20180613000)	PCN Date:	June 21, 2018	
Customer Contact:	PCN Manager	···· -	Dept:	Quality Services	
Change Type:					
Assembly Site		Design		Wafer Bump Site	
Assembly Process		Data Sheet		Wafer Bump Material	
Assembly Materia		Part number		Wafer Bump Process	
		change			
Mechanical Specif	ication	Test Site		Wafer Fab Site	
Packing/Shipping,		Test Process		Wafer Fab Materials	
	\square	Documentation		Wafer Fab Process	
Notification Details					
Description of Change: Texas Instruments Incorporated is announcing an information only notification.					
Safety Manual for bq76PL455A-Q1					
Changes from D Revision (March 2017) to E Revision Page • Added Using OWD (Open Wire Detection), Using FETCheck, Using a Combination of WINCOMP and FETCHECK, and Using External Hardware Components sections to the BatBroken section to expand more on the different implementations of the "BatBroken" safety measure. 25					
Added Using OWD (Oper Using External Hardware	n Wire Detection), Usi Components section	ing FETCheck, Using a Cor s to the BatBroken section t	o expand more on the	P and FETCHECK, and different implementations	
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